

ESD (CHARGE DEVICE MODE) TEST REPORT

Company : 武汉力源半导体有限公司

Address : 上海长宁区天山西路 567 号神州智慧大厦 3 楼力源

Model Name : CW32F030

Date Received : July 7, 2021

Date Tested : July 7, 2021

TESTING LABORATORY IS APPROVED BY:

IECQ Certificate of Approval No.: IECQ-L DEKRA 17.0004-01 For Independent Test Laboratory
According to ISO/IEC 17025

WE HEREBY CERTIFY THAT:

The test(s) shown in the attachment were conducted according to the indicating procedures.
We assume full responsibility for the accuracy and completeness of these tests and vouch
for the qualifications of all personnel performing them.

	Name	Signature	Date
Testing Engineer	Peter Pan	<i>Peter Pan</i>	2021/7/7
Approving Manager	Peng_Zhao	<i>Peng Zhao</i>	2021/7/7

Note :

1. This report will be invalid if reproduced in whole or in part.
2. This report refers only to the specimen(s) submitted to test, and is invalid if used separately.
3. This report is ONLY valid with the examination seal and signature of this institute.
4. The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant.
5. The failure criteria of all ESD tests should be based on the result of parametric and functional testing conducted by the customer, which follows the statement of international standards. Thus, the judgment of the curve traces provided in this report is for reference ONLY.



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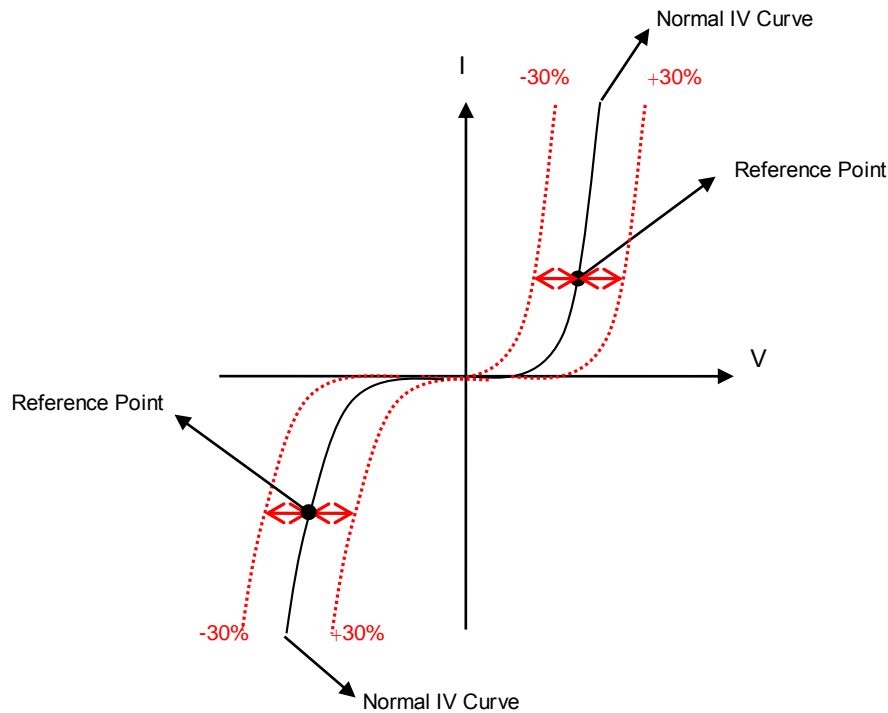
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1. GENERAL INFORMATION

1.1 DESCRIPTION OF UNIT

MANUFACTURER	: 武汉力源半导体有限公司
DEVICE NAME	: CW32F030
PACKAGED / PIN COUNT	: LQFP48
REFERENCE DOCUMENT	: JEDEC EIA/JESD22-C101F
TEST VOLTAGE	: 2000V(±);
SAMPLE QUANTITY	: 3 pcs
Functional Test	: Performed by Customer
FAILURE CRITERIA (Reference Only)	: ±30% voltage shift at reference point before/after zapping
Humidity at the test head	: ≤ 30%RH

※ Failure Judgment: Voltage shift over ±30% at reference point.



2. ESD (CHARGE DEVICE MODE) TEST

2.1 TEST EQUIPMENT

Test Equipment	Equipment S/N	Calibration Date:	Recommended Due Date:
THERMO ORION 3	1606269	March 24,2021	March 23,2022

2.2 LABORATORY AMBIENCE CONDITION

 Temperature : 25°C^{+3°C}_{-5°C}

Relative humidity : 55%±10% (RH)

2.3 REFERENCE DOCUMENT

The test is based on JEDEC EIA/JESD22-C101F

2.4 TEST CONDITION

2000V(±)×3pcs;

2.5 SUMMARY OF TEST

Test Model : CDM	ESD Sensitivity Passed : <u>±2000V</u>			JEDEC EIA/JESD22-C101F Classification Class : <u>C3</u>
Test condition	Sample No.	Curve Trace Pass Volts	FT Testing Pass Volts	Class C0A <125 V Class C0B 125 to <250 V Class C1 250 to <500 V Class C2 500 to <1000 V Class C3 1000 V or greater
2000V(±)×3pcs;	#C1-#C3	±2000	Unknown	

Discharge Pins All Pins;

2.6 CONTENTS OF TEST(CURVETRACE TESTING RESULTS)

±30% voltage shift at reference point before/after zapping CDM(±2000V);			
Tested Pin	Sample No. & Failed Volt (V)		
	#C1	#C2	#C3
All Pins	I/V PASS	I/V PASS	I/V PASS